

Notice of Allowability	Application No.	Applicant(s)	
	10/605,379	BICKFORD ET AL.	
	Examiner Tuyen To	Art Unit 2825	77

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTO-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. This communication is responsive to 09/26/2003.
2. The allowed claim(s) is/are 1-31.
3. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) All
 - b) Some*
 - c) None
 of the:
 1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) including changes required by the Notice of Draftperson's Patent Drawing Review (PTO-948) attached
 - 1) hereto or 2) to Paper No./Mail Date _____.
 - (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. Notice of References Cited (PTO-892)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)
3. Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____
4. Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. Notice of Informal Patent Application (PTO-152)
6. Interview Summary (PTO-413),
Paper No./Mail Date _____.
7. Examiner's Amendment/Comment
8. Examiner's Statement of Reasons for Allowance
9. Other _____.


VUTHE SIEK
PRIMARY EXAMINER

DETAILED ACTION

This is a response to the communication filed on 09/26/2003. Claims 1-31 are pending.

Examiner's amendment

1. In claims:

Claim 5, line 3, after "; ", insert --and --.

Claim 8, line 3, after "; ", insert -- and --.

Claim 16, line 3, after "; ", insert -- and --.

Claim 25, line 4, after "; ", insert -- and --.

Claim 28, line 4, after "; ", insert --and --.

2. In Specification:

Page 12, line13, delete "(5)" and insert -- (4) --.

Allowable Subject Matter

3. Claims 1-31 are allowable over the prior art of record.

4. The following is an examiner's statement of reasons for allowance:

Claims 1 and similarly recited 21 are allowed because the prior art of record does not teach or fairly suggest a method for predicting manufacturing yield for a proposed integrated circuit, having a combination of steps including the following limitations recited in claim 1 and 21:

(a) providing a multiplicity of different integrated circuit library elements in a design database, each library element linked to a corresponding normalization factor in said design database;

- (c) generating an equivalent circuit count of said proposed design based on said normalization factors and a count of each different library element included in said proposed design; and
- (d) calculating a predicted manufacturing yield based on said equivalent circuit count, a predicted density of manufacturing defects and an area of said proposed integrated circuit chip.

Claim 12 is allowed because the prior art of record does not teach or fairly suggest a method for predicting manufacturing yield for an integrated circuit, having a combination of steps including the following limitations recited in claim 12:

- (a) assigning different integrated circuit library elements into circuit types according to a user defined list of attributes;
- (b) compiling a set of yield limiting parameters for each circuit type and determining a normalization factor for each circuit type;
- (d) generating an equivalent circuit count of said proposed design based on said normalization factors for said circuit types and a count of each different library element included in said proposed design; and
- (e) calculating a predicted manufacturing yield based on said equivalent circuit count, a defect density value and an area of said proposed integrated circuit chip.

5. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should

preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tuyen To whose telephone number is (571) 272-8319. The examiner can normally be reached on 9:00am-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on (571) 272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tuyen To



Patent examiner

AU 2825



VU THE SIEK
PRIMARY EXAMINER